AMENDMENTS TO THE SPECIFICATION

Please replace Paragraph **[0001]** of the original specification with the following amended Paragraph:

[0001]   This application discloses subject matter related to the subject matter disclosed in the following commonly owned co-pending patent application: "System and Method for Testing a Circuit Design," ~~filed~~ _____, ~~Application No.:~~ _____ filed October 1, 2003, Application No.: 10/676,859 (Docket Number 200209135-1), in the names of Ryan C. Thompson, John W. Maly, and Zachary S. Smith; and "System and Method for Generating a Test Case," ~~filed~~ _____, ~~Application No.:~~ _____ filed October 1, 2003, Application No.: 10/676,236 (Docket Number 200209280-1), in the names of Ryan C. Thompson, John W. Maly, and Zachary S. Smith, both of which are hereby incorporated by reference for all purposes.

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Please replace Paragraph **[0018]** of the original specification with the following amended Paragraph:

[0018]   Additionally, command line settings may also be provided in the generated test case 216 which relate to the starting and stopping of specific actions in the processor models 218 and the defining of testing conditions, such as the number of threads, for example.   Further information relative to the generation of simulation parameters for multithreaded test cases may be found in the aforementioned patent application entitled "System and Method for Generating a Test Case," ~~filed _____, Application No.:_____~~ filed October 1, 2003, Application No.: 10/676,236 (Docket Number 200209280-1), in the names of Ryan C. Thompson, John W. Maly, and Zachary S. Smith, which is hereby incorporated by reference for all purposes.

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Please replace Paragraph **[0021]** of the original specification with the following amended Paragraph:

[0021]   When debugging a test case failure or a particular model, it is useful to compare the values in the instruction summary to the actual values produced when the test case was executed in the process development test environment.   For instance, the interfaceable listing of the uncommitted references and their respective values in the interfaceable summary is of particular aid to the comparator 226 during the debugging operations 230 and 232. In particular, by adding a reference to each unique temporarily uncommitted value in the interfaceable summary and summarizing the uncommitted references, a dynamic transparency is added to the processing of the registers and addresses that allows a comparator, such as a programmer or programmer employing an expert system, to determine the progression of any temporarily uncommitted value at different points in the execution of the test case. This temporal transparency provided by the systems and methods described herein translates into an efficient debugging process. Further details relative to the debugging operations within the context of test case generation may be found in the aforementioned co-pending patent application entitled "System and Method for Testing a

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Circuit Design," ~~filed _____, Application No.:~~ ~~_____~~ filed October 1, 2003, Application No.: 10/676,859 (Docket Number 200209135-1), in the names of Ryan C. Thompson, John W. Maly, and Zachary S. Smith, which is hereby incorporated by reference for all purposes.

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